	<u>ESC</u>	<u> </u>	D	OCUMENT	CHANGE REQUEST			
DCR number	732	Changes re	quired for: Ge	neral	Originator: Steve Thacker			
Date: 2015/07	7/14	Date sent: 2012/06/18			Organisation: ESCC Executive			
Status: IMPLE	EMENTED				Secretariat			
Title:	Capacitors Fixed Chips Ceramic Dielectric Type I, based on type 0805							
Number:	3009/003 Issue:		Issue:	5				
Other documen	documents affected:							
Page:								
Total reformat/re-write of ESCC Detail Specification 3009/003 issue 4 as part of the ongoing conversion of legacy ESA/SCC specifications to the ESCC format as well as reflecting changes resulting from the conversion of ESCC Generic Specification No. 3009 issue 1 (per DCR695).								
-	The layout, format and general content of 3009/003 issue 5 is based on other converted ESCC Detail Specifications (see attached for proposed 3009/003 issue 5 Draft A).							
The technical content of ESCC 3009/003 issue 5 remains closely based on the original ESCC 3009/003 issue 4 except as detailed herein.								
Paragraph:	Paragraph:							
see below								
Original wording	g:							
see original ESCC 3009/003 issue 4								
Proposed wording:								
	al reformat of this Detail Specification (from the range of various ESCC Detail Specifications, 3009/xxx, for capacitors der Generic Specification No. 3009) as part of the ongoing conversion to the ESCC format.							
See below for s	See below for summary of changes, also see attached the proposed 3009/003 Issue 5 Draft A.							
Note: known support for active procurement against this specification includes the following Manufacturers: • AVX-TPC/France (ESCC Qualified for Variant 01, 03, 06) • Eurofarad/France (is willing to support procurement). • Syfer/UK (is willing to support procurement of Variant 01 & 06).								
Summary of changes to the current format, layout and content is as follows:								
1) General Rewording and	1) General Rewording and restructure of various sections and paragraphs of the specification, plus other editorial changes based on							

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the layout and editorial content of other D	Detail Specifications	already converted to E	ESCC format.				
In addition, editorial and technical amendments resulting from the changes made to the test requirements of the Generic Specification No. 3009. Specific amendments include: • Table 3: Delete Insulation Resistance, and Temperature Coefficient for each capacitance value [ Test No. 5(i) ] (due to SCC level B being deleted) • Para. 4.7.1 & Table 4 is deleted (due to SCC level B being deleted) • Table 6 only includes specified electrical measurement requirements as required for the various Chart F4 Qual level tests (editorial change) • Table 6: Adhesion is renamed as Robustness of Terminations • Table 6: add note that the capacitance values recorded during Mounting may be used as initial measurements for other tests (to provide the same flexibility included in 3009 issue 1)							
<ul> <li>2) Table 1(a), Para 4.4.1, Figure 2, (Para 1.4.2 in issue 5)</li> <li>All component range and selection options (including Variant, style, capacitance, tolerance, voltage, dimensions, terminal materials, weight) are brought together under a single Para. (editorial changes for clarification purposes)</li> </ul>							
3) Table 1(a), Table 1(b), Para 4.5.3.3 The range of components including Capa Syfer: Note – The Syfer range is as follows: 16V: 1pF to 6.8nF 25V: 1pF to 6.8nF 25V: 1pF to 4.7nF 50V: 1pF to 2.7nF 100V: 1pF to 1.8nF 200V: 1pf to 680pF	acitance and Rated \	/oltage is expanded to	o also include the range supported by				
4) Figure 3. Functional Diagram is simplif	fied (i.e. symbol 'C' i	s removed)					
5) Para 3. Delete added symbol (editorial	I change: as they are	e no longer required b	y ESCC 21300)				
6) Para 4.2.2(a). Delete irrelevant deviation	on.						
7) Para 4.4.1 Solder coating definition is simplified to be Delete statements, "All the above Variant	•		ariants 06 is the preferred termination				



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finish for the specified chip size (see Figure 2)". (remove unnecessary and inappropriate comments; editorial change)

8) Table 2 Note 1: Amend range to be for C 50pF ... (to be consistent with the full range covered by the spec: 1pF)

9) Table 3 Temperature Coefficient - Test No. 5(ii) (Para 2.3.2 in issue 5)

The default test conditions per the generic spec now apply. i.e. the +/-30ppm/C limit applies over the full temperature range: -55C to +125C (was only specified for temp range +20C to +125C)

Amend remark to read "... 5 components from each manufacturing lot ..." (instead of "5 parts for each dielectric lot") (to be consistent with ESCC terminology & the Generic spec).

Amend Note 4 to clarify that TC is not specified for low values Cn 20pF.

10) Table 5 (Para 2.5 in issue 5). Delete test conditions that are already specified in the Generic spec (Temperature & Voltage).

11) Appendix A. Delete appendix A for Vitramon/UK (who longer support ESCC procurement)(Appendix B is renamed as Appendix A, for AVX/TPC (F))

Justification:

Part of the ongoing conversion of legacy ESA/SCC specifications to the ESCC format. Amendments are made to the format and presentation to be consistent with the various other ESCC Detail Specifications, already converted to ESCC format, as well as the ESCC Generic Specification No. 3009 issue 2.

See also change details for justification for specific items above.

Attachments:	
3009003_draft_6c_for_final_review.docx, 3009003_draft_5a_in_review.pdf	
Modifications:	
Draft 6 c is approved	
Approval signature:	
R. C. Havi-9	
Date signed:	
2015-07-14	